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Key indicators

Single-crystal X-ray study T = 296 KMean σ (C–C) = 0.004 Å R factor = 0.040 wR factor = 0.035 Data-to-parameter ratio = 13.8

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

(*E*)-1-(2-Hydroxyphenyl)-3-(3,4,5-trimethoxyphenyl)prop-2-en-1-one

The title compound, $C_{18}H_{18}O_5$, was prepared by the condensation of 2-hydroxyacetophenone with 3,4,5-trimeth-oxybenzaldehyde. The trimethoxyphenyl and hydroxyphenyl rings of the chalcone system are approximately coplanar.

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Comment

Chalcones, particularly those with hydroxy substituents, are important components of numerous natural products that show interesting biological and pharmacological activities (Kumar *et al.*, 2003; Liu *et al.*, 2001). They are also important intermediates in organic synthesis, such as in the use of 2-hydroxychalcones in the synthesis of flavanones (Chaturvedi *et al.*, 1992). We report here the structure of the title chalcone, (I).



The two aromatic rings are nearly coplanar [interplanar angle $15.33 (12)^{\circ}$]. Furthermore, the hydroxyphenyl ring subtends an angle of $5.39 (14)^{\circ}$ at the central C–C=C–C section of the molecule; the corresponding angle for the methoxyphenyl ring is 9.95 (14)°, with the two benzene rings rotated in opposite directions. A classic intramolecular hydrogen-bonding interaction (Table 2) involves the hydroxy group and the adjacent ketone O atom to form a sixmembered ring that promotes the planarity of the molecule.

Experimental

Compound (I) was prepared through condensation of 2-hydroxyacetophenone (5 mmol, 1.57 g) with 3,4,5-trimethoxybenzaldehyde (5 mmol, 0.68 g) in 20% NaOH solution (1 ml), using phase transfer TBAB (tetrabutylammonium bromide; 0.75 mmol, 0.25 g) under microwave irradiation for 5 min (yield 73%, m.p. 419–421 K). The reaction mixture was poured into water (100 ml) and filtered. After the usual work-up, the product was purified by chromatography on silica gel and crystals of (I) suitable for X-ray diffraction were obtained by slow evaporation of a 95% ethanol solution.

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Crystal data

 $C_{18}H_{18}O_5$ $M_r = 314.32$ Monoclinic, $P2_1/c$ a = 12.686 (2) Å b = 8.588 (1) Å c = 15.422 (3) Å $\beta = 108.00$ (1)° V = 1598.1 (5) Å³ Z = 4

Data collection

Siemens *P*4 diffractometer ω scans Absorption correction: none 3470 measured reflections 2989 independent reflections 984 reflections with *I* > 2 $\sigma(I)$ *R*_{int} = 0.030

Refinement

Refinement on F^2 $w = 1/[\sigma^2(F_{\rm o}{}^2) + (0.001P)^2$ $R[F^2 > 2\sigma(F^2)] = 0.040$ wR(F²) = 0.035 + 0.075P] where $P = (F_0^2 + 2F_c^2)/3$ S = 0.80 $(\Delta/\sigma)_{\rm max} = 0.001$ $\Delta \rho_{\rm max} = 0.16$ e Å 2989 reflections $\Delta \rho_{\rm min} = -0.12 \text{ e } \text{\AA}^{-3}$ 216 parameters H atoms treated by a mixture of Extinction correction: SHELXL97 independent and constrained Extinction coefficient: 0.0061 (3) refinement

 $D_x = 1.307 \text{ Mg m}^{-3}$

Cell parameters from 33

 $0.35 \times 0.30 \times 0.16 \ \text{mm}$

Mo $K\alpha$ radiation

reflections

 $\theta = 3.0-14.5^{\circ}$ $\mu = 0.10 \text{ mm}^{-1}$

T = 296 (2) K

Block, yellow

 $\theta_{\rm max} = 25.5^{\circ}$

 $h = 0 \rightarrow 15$

 $k = 0 \rightarrow 10$

 $l = -18 \rightarrow 17$

3 standard reflections

every 97 reflections

intensity decay: 1.9%

Table 1

Selected geometric parameters (Å, °).

O1-C1	1.350 (3)	C8-C9	1.323 (2)
O1-H10	0.832 (10)	C9-C10	1.466 (3)
O2-C7	1.239 (3)		
C12-O3-C16	117.7 (2)	O2-C7-C6	119.9 (3)
C13-O4-C17	113.1 (2)	C8-C9-C10	127.8 (3)
O2-C7-C8	120.4 (3)		
01-C1-C2-C3	-179.7(3)	02-C7-C8-C9	8.2 (4)
C3-C4-C5-C6	0.0 (4)	C8-C9-C10-C15	1.1 (4)
O1-C1-C6-C7	1.6 (4)	C17-O4-C13-C14	77.0 (3)

Table 2

Hydrogen-bond geometry (Å, °).

$D-\mathrm{H}\cdots A$	D-H	$H \cdots A$	$D \cdots A$	$D - \mathbf{H} \cdots A$
O1−H1 <i>O</i> ···O2	0.83 (1)	1.79 (2)	2.521 (3)	146 (3)

Crystals of (I) were weakly diffracting, with only 33% of the reflections considered to be observed. However, this fact did not adversely affect the solution and refinement processes. With the exception of H1*O*, which was located and freely refined, H atoms were positioned geometrically and allowed to ride on their parent atoms at C–H distances of 0.93 or 0.96 Å with $U_{\rm iso(H)} = 1.2U_{\rm eq}(C)$.

Data collection: *XSCANS* (Siemens, 1994); cell refinement: *XSCANS*; data reduction: *SHELXTL* (Sheldrick, 1997*b*); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997*a*); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997*a*); molecular graphics: *SHELXTL*; software used to prepare material for publication: *SHELXTL*.

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Figure 1

The molecular structure of (I), showing 50% probability displacement ellipsoids and the atom-numbering scheme.



Figure 2	
The molecular packing of (I). H atoms have been	omitted.

References

- Chaturvedi, R., Patil, P. N. & Mulchandani, N. B. (1992). *Indian J. Chem. Sect. B*, **31**, 340–341.
- Kumar, S. K., Hager, E., Pettit, C., Gurulingappa, H., Davidson, N. E. & Khan, S. R. (2003). J. Med. Chem. 46, 2813–2815.
- Liu, M., Wilairat, P. & Go, M. L. (2001). J. Med. Chem. 44, 4443-4445.
- Sheldrick, G. M. (1997a). SHELXS97 and SHELXL97. University of Göttingen, Germany.
- Sheldrick, G. M. (1997b). SHELXTL. Version 5.1. Bruker AXS Inc., Madison, Wisconsin, USA.

Siemens (1994). XSCANS. Version 2.1. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.